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(12) United States Design Patent
Ihara

(10) **Patent No.: US D724,214 S**
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(54) **ANALYZING MACHINE HAVING X-RAY**

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(**) Term: **14 Years**

(21) Appl. No.: **29/471,850**

(22) Filed: **Nov. 6, 2013**

(30) **Foreign Application Priority Data**

Aug. 27, 2013 (JP) 2013-019564

(51) **LOC (10) Cl.** **24-01**

(52) **U.S. Cl.**
USPC **D24/158**; D24/216

(58) **Field of Classification Search**
USPC D24/158–161, 185, 186, 216; 378/44–47, 64, 66, 88
See application file for complete search history.

(56) **References Cited**

U.S. PATENT DOCUMENTS

D424,199 S *	5/2000	Wells	....	D24/158
D441,080 S *	4/2001	Herekar et al.	....	D24/158
D489,816 S *	5/2004	Ross	....	D24/186
D508,565 S *	8/2005	Nephin et al.	....	D24/186
D647,209 S *	10/2011	Muller et al.	....	D24/216
D689,193 S *	9/2013	Shinohara et al.	....	D24/216
D702,350 S *	4/2014	Nasella	....	D24/158
2013/0272498 A1*	10/2013	Goto et al.	....	378/45

* cited by examiner

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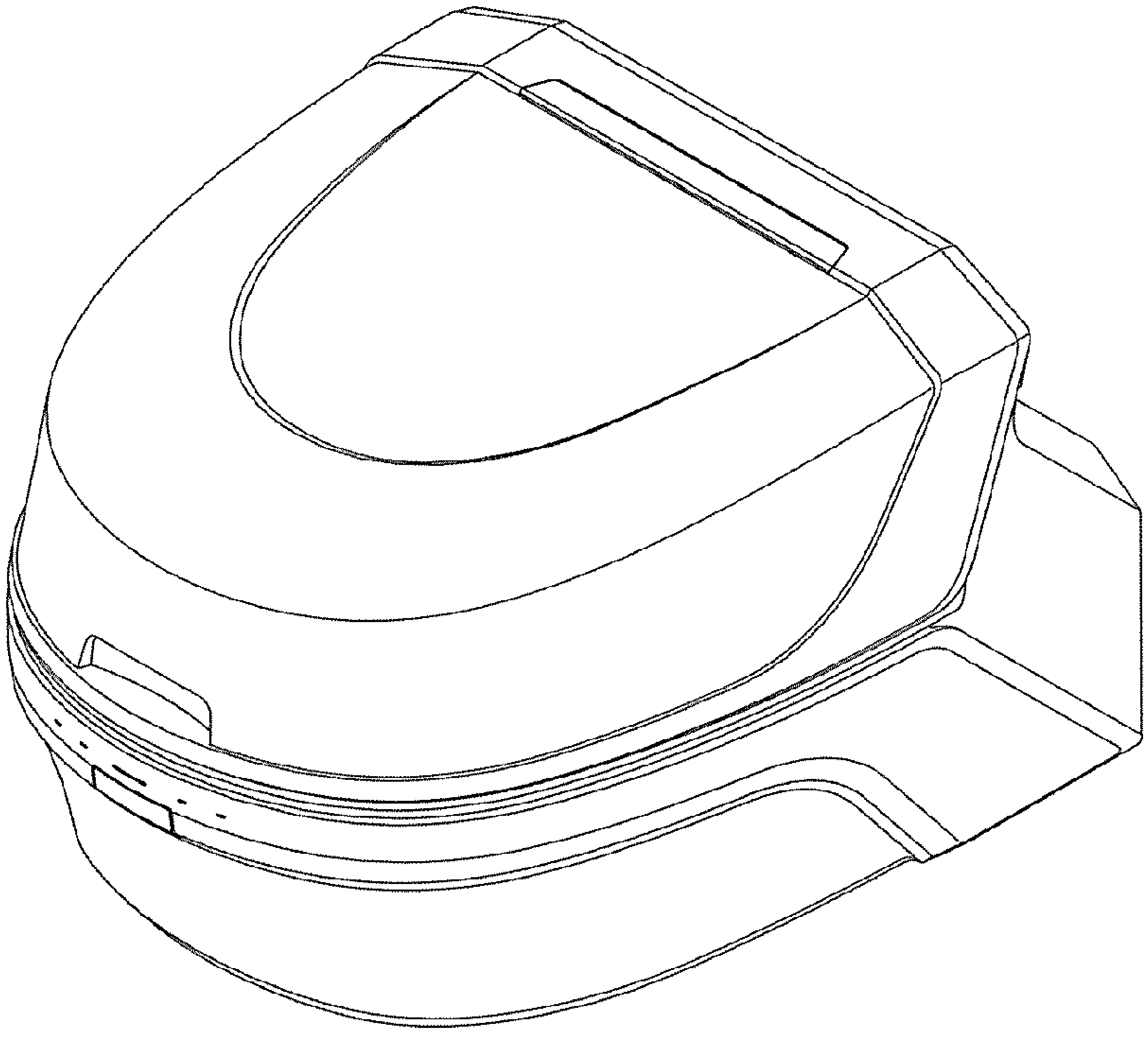
(57) **CLAIM**

The ornamental design for an analyzing machine having X-ray, as shown and described.

DESCRIPTION

FIG. **1** is a perspective view of an analyzing machine having X-ray showing my new design;
FIG. **2** is another perspective view thereof;
FIG. **3** is a front view thereof;
FIG. **4** is a rear view thereof;
FIG. **5** is a left side view thereof;
FIG. **6** is a right side view thereof;
FIG. **7** is a top view thereof; and,
FIG. **8** is a bottom view thereof.

1 Claim, 8 Drawing Sheets



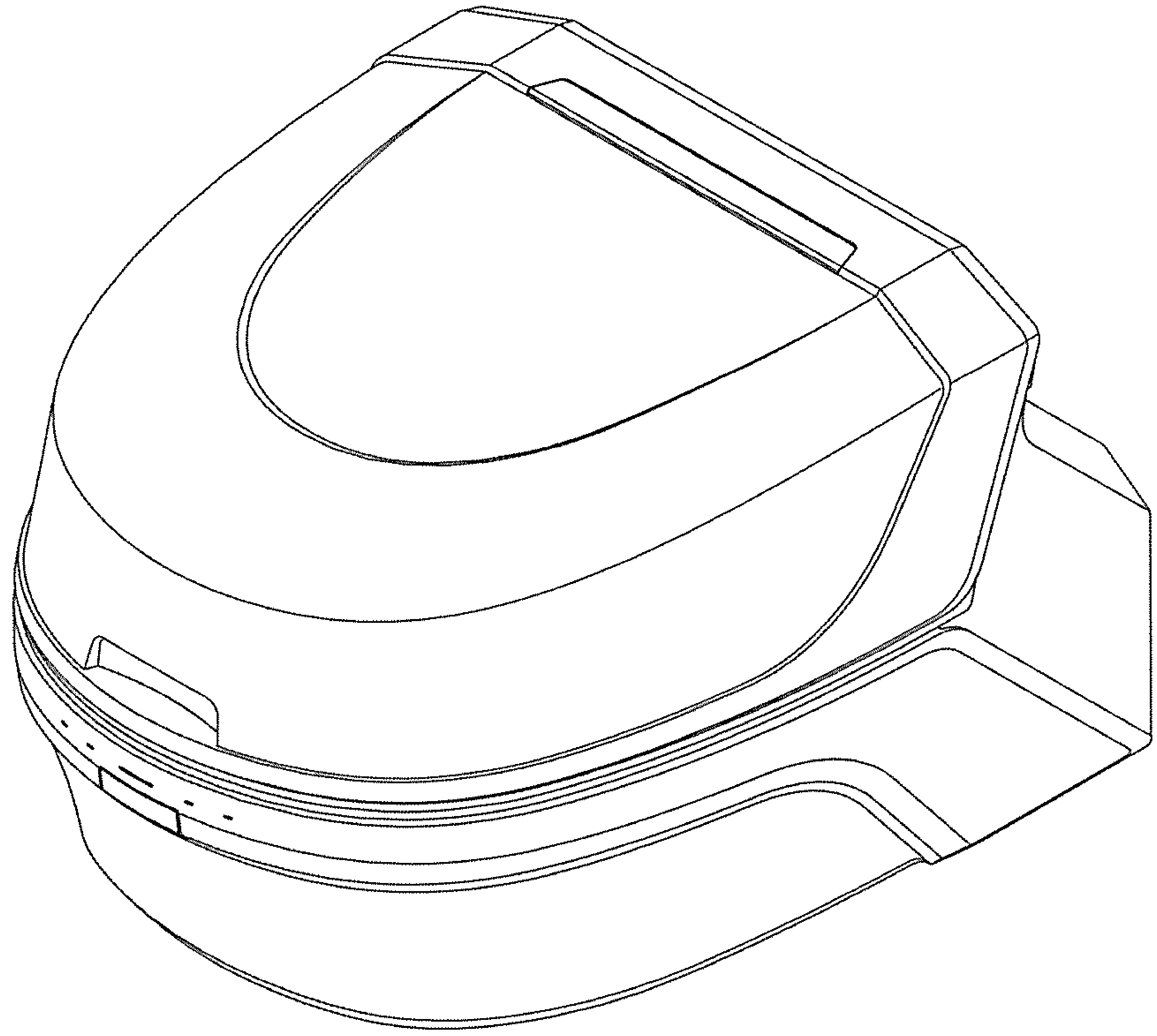


FIG.1

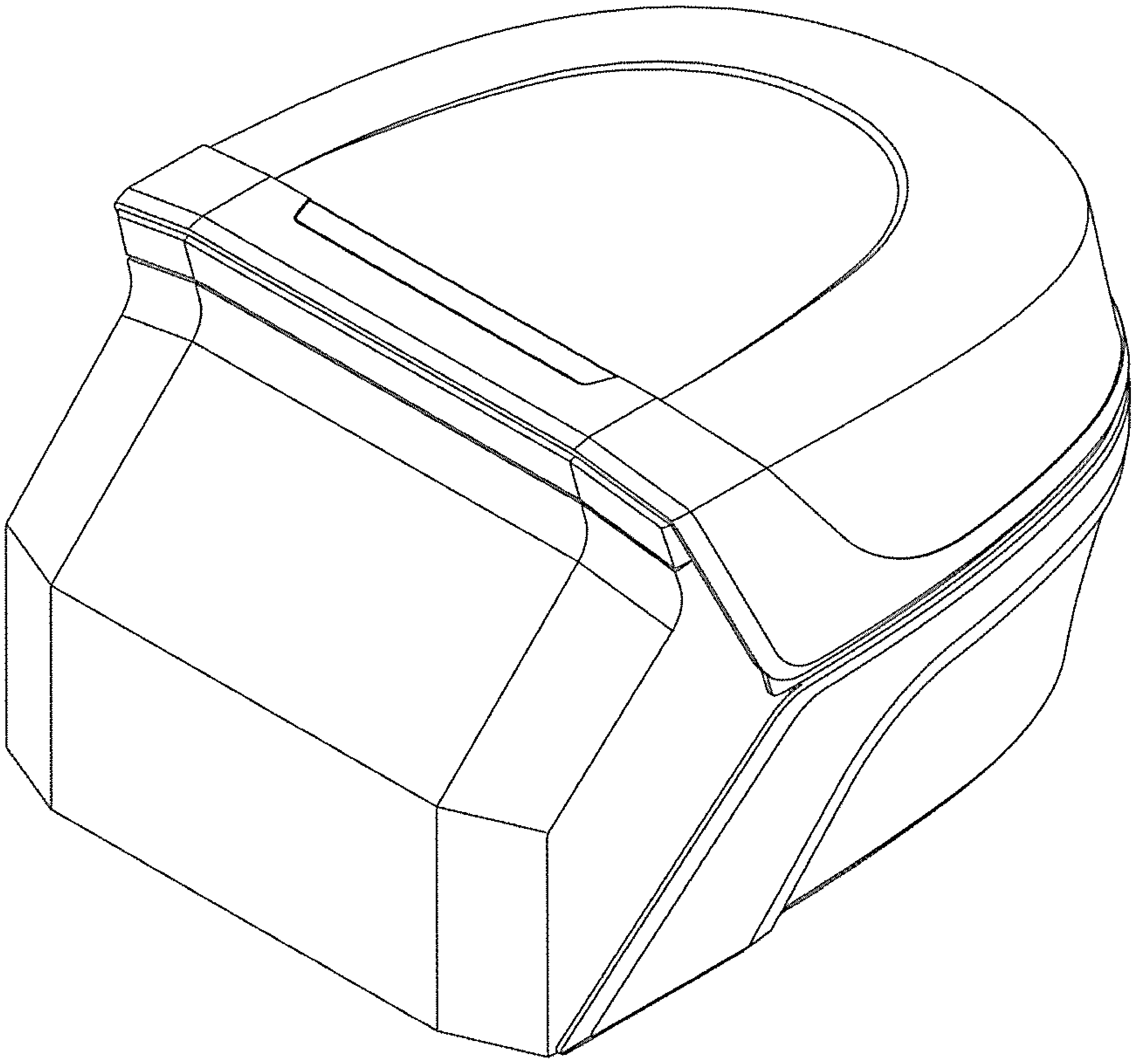


FIG.2

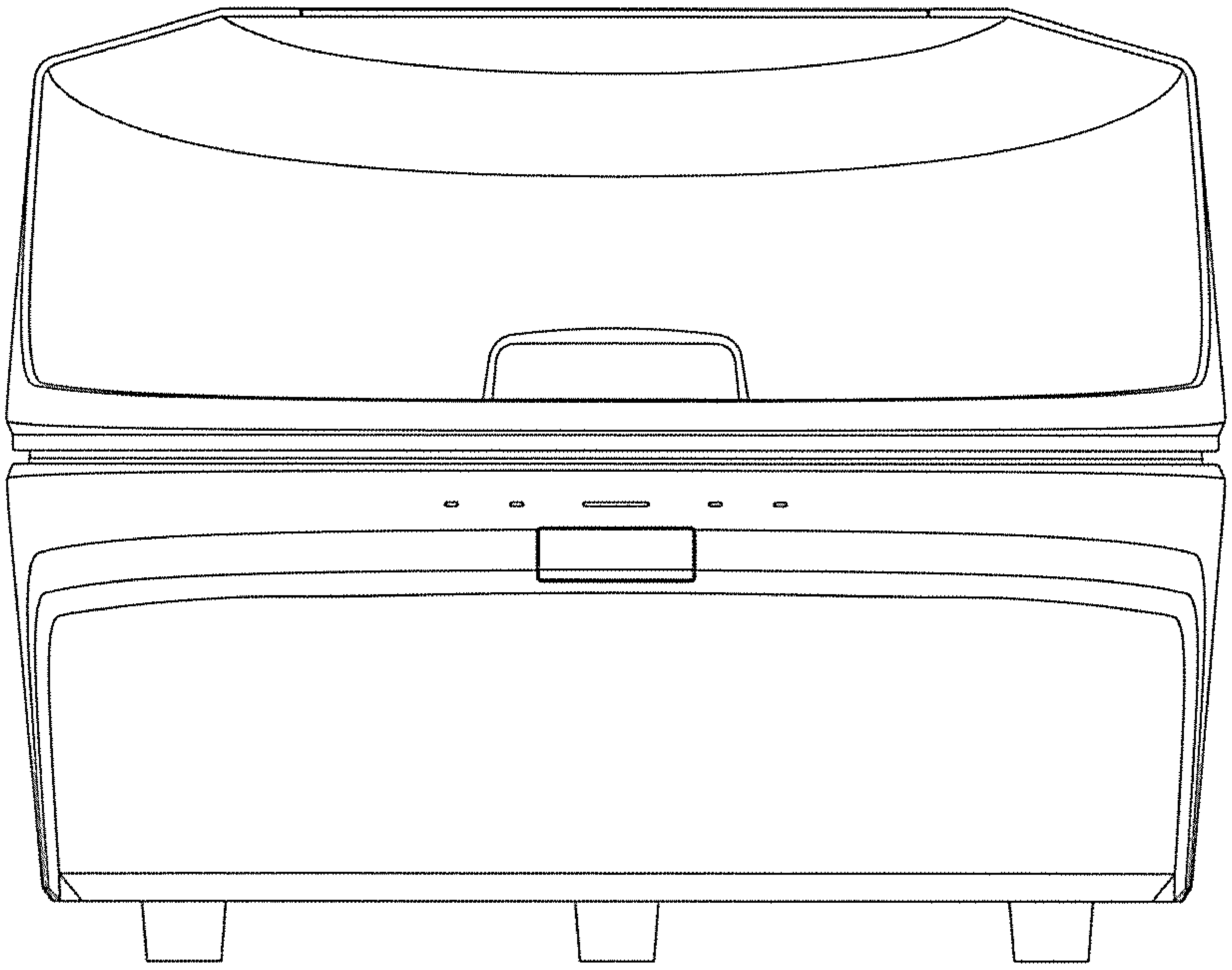


FIG.3

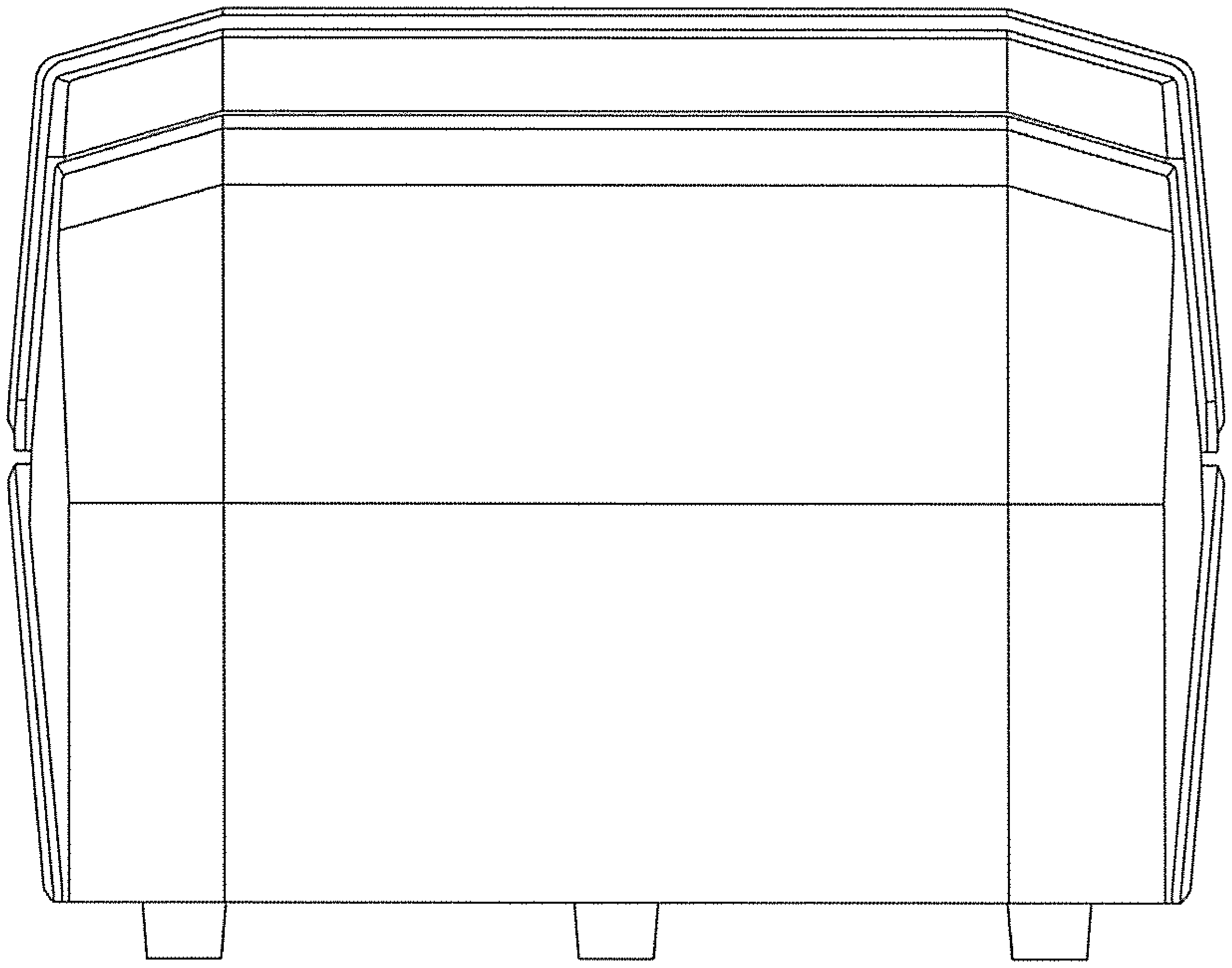


FIG.4

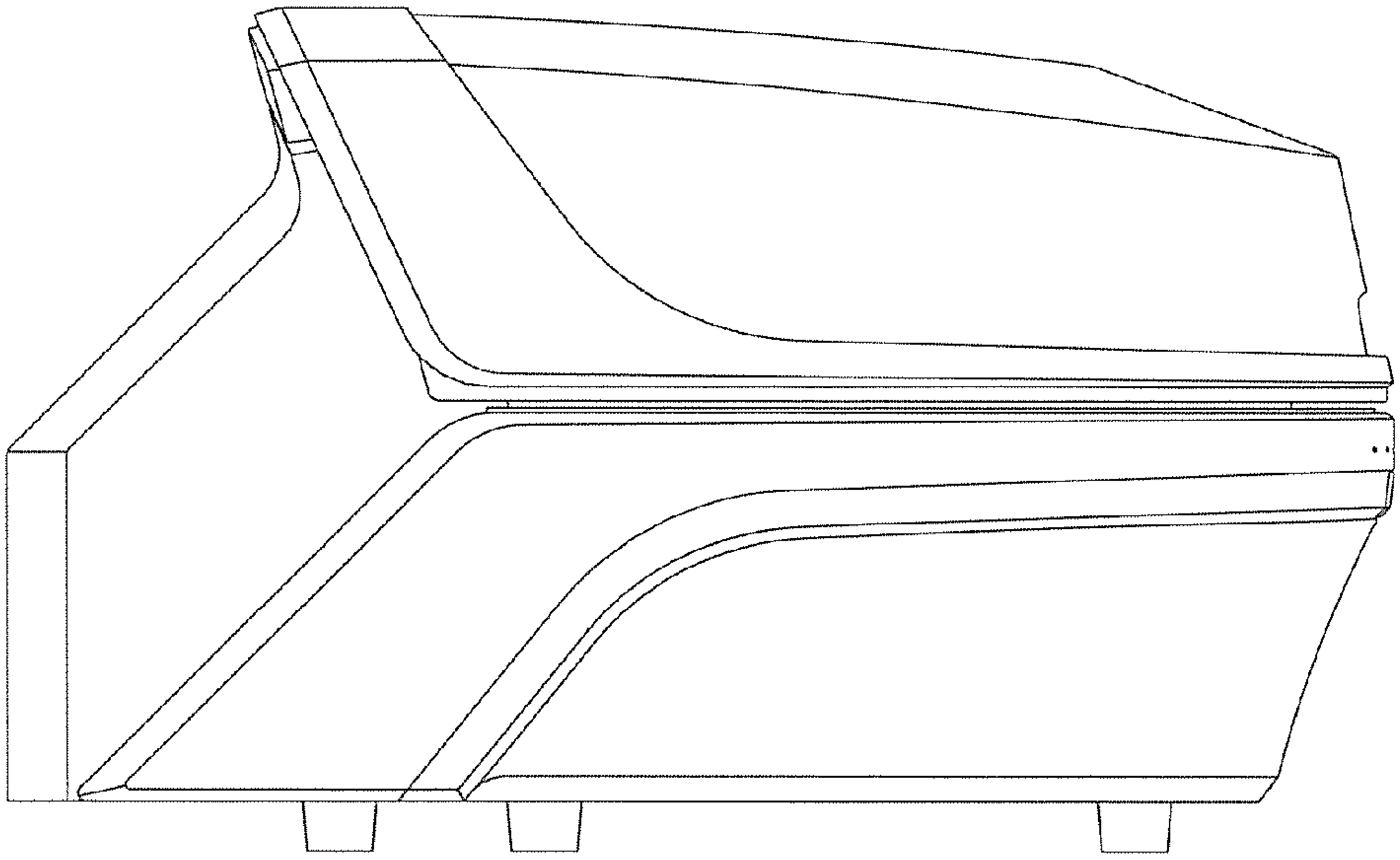


FIG.5

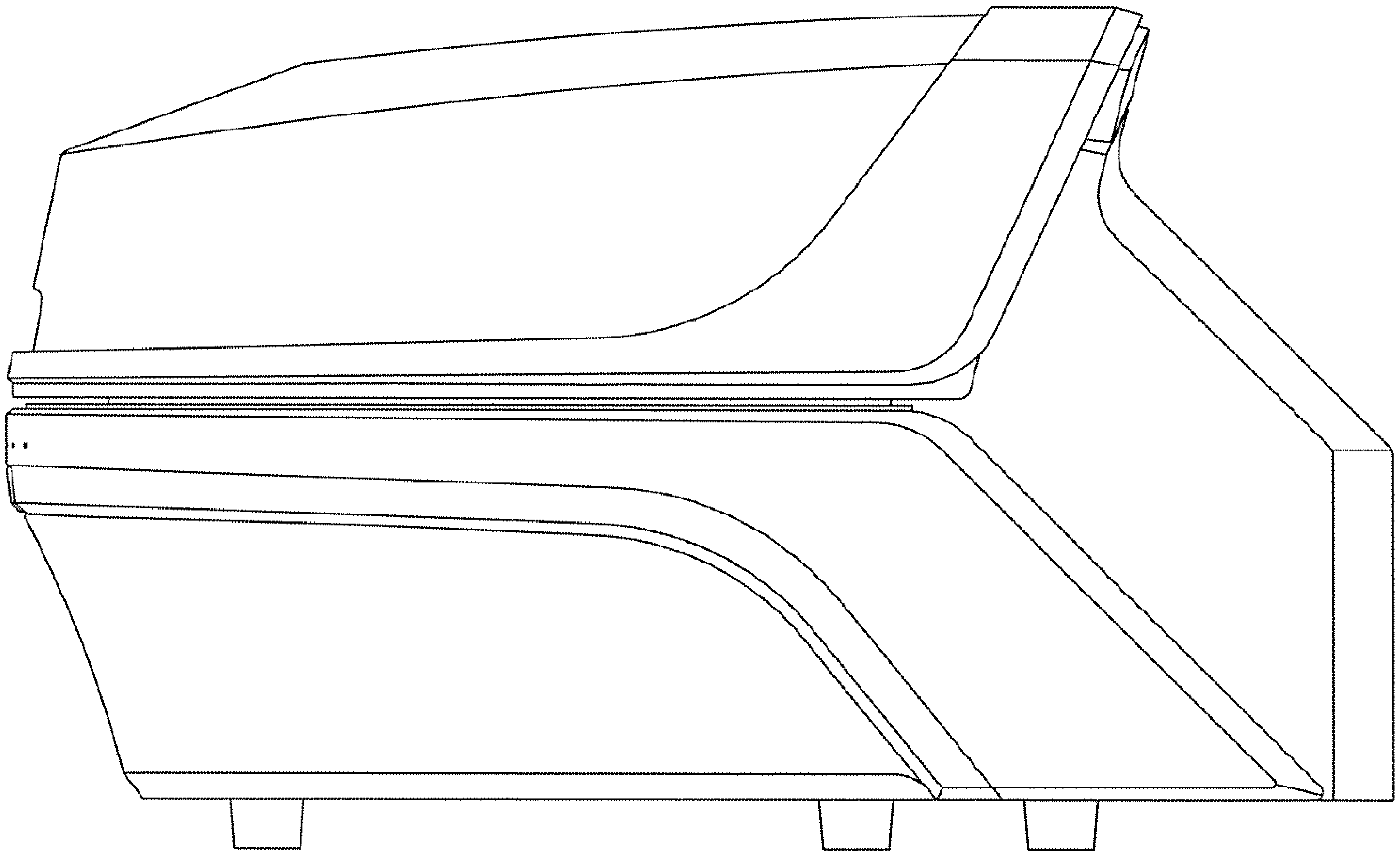


FIG.6

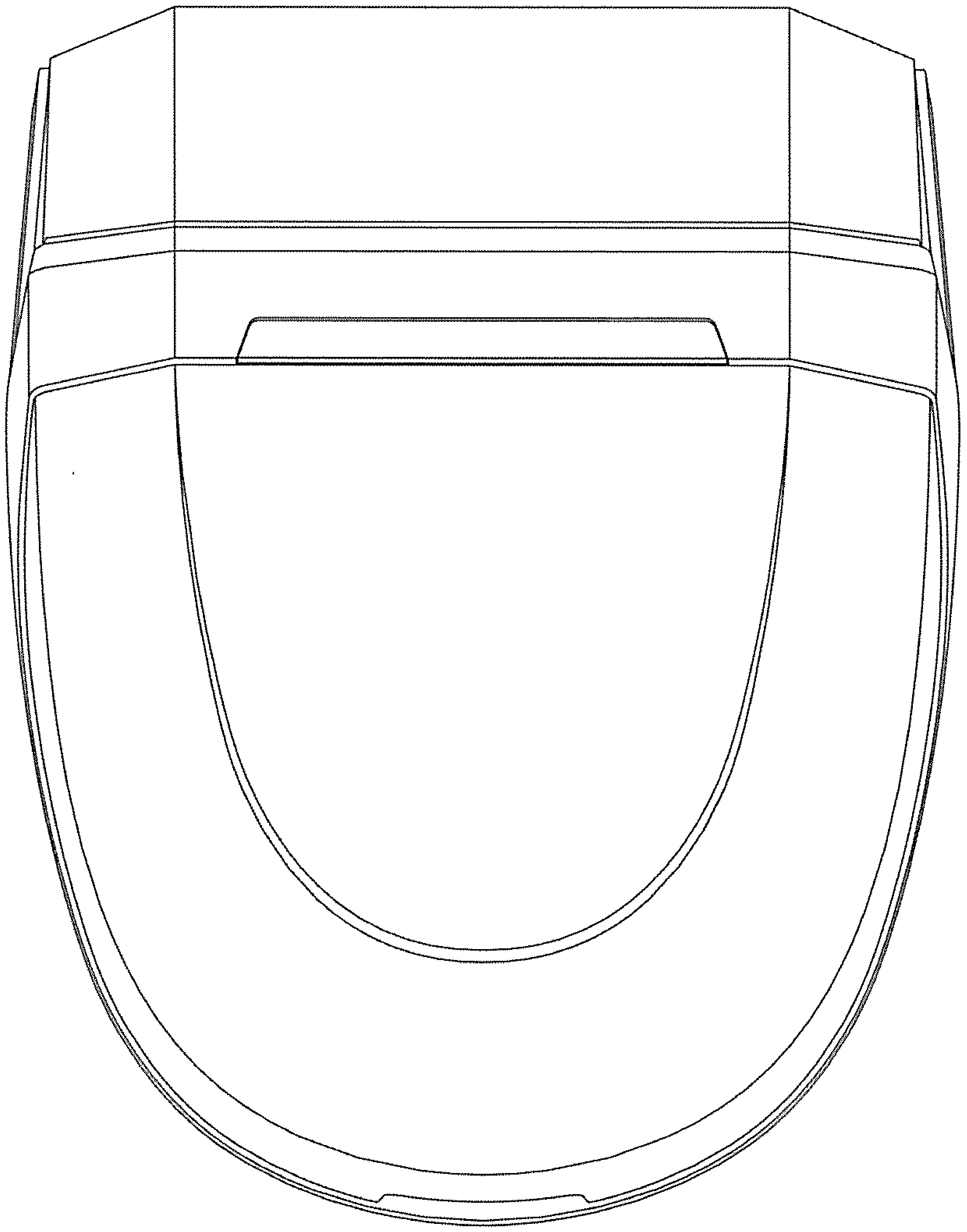


FIG.7

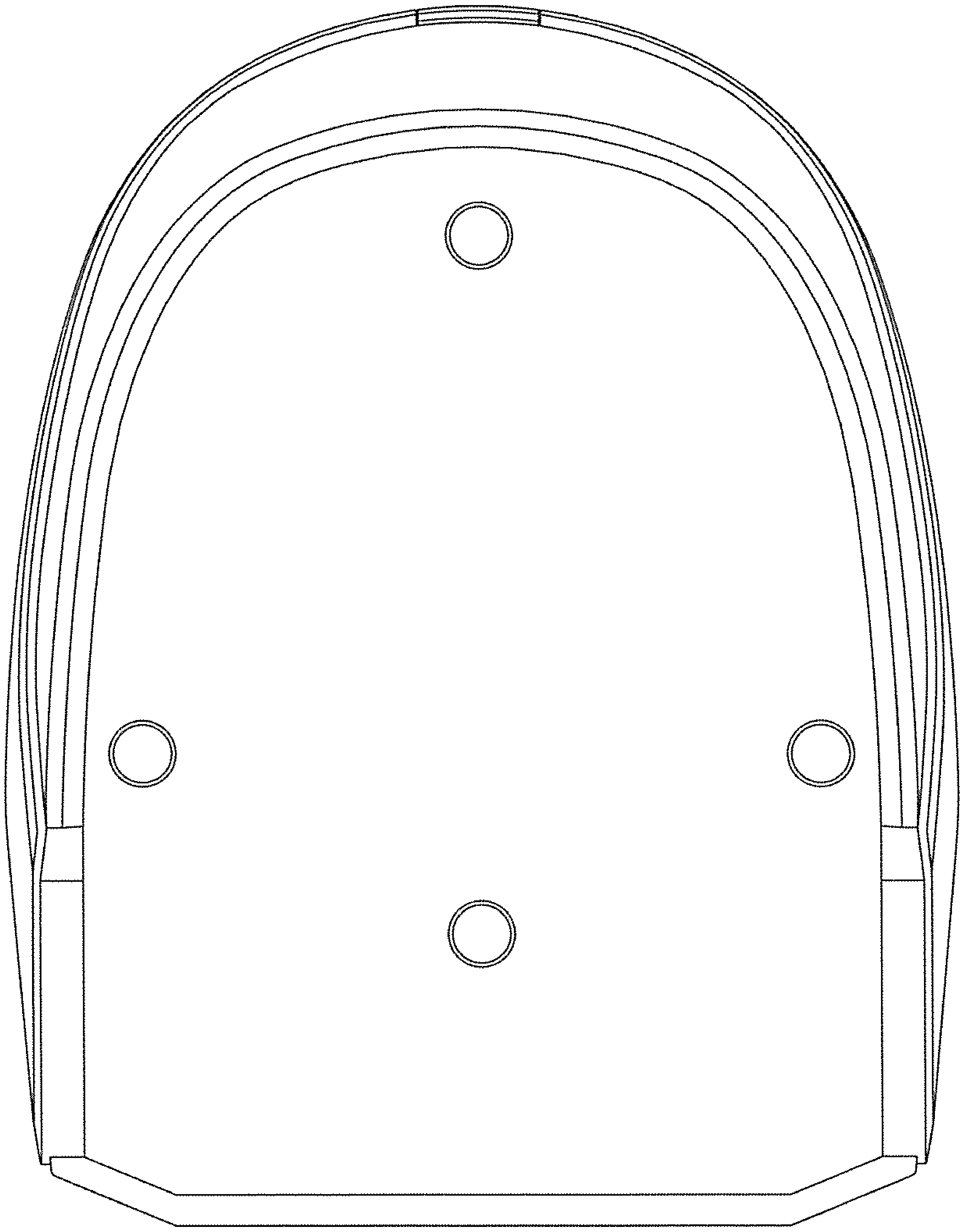


FIG.8